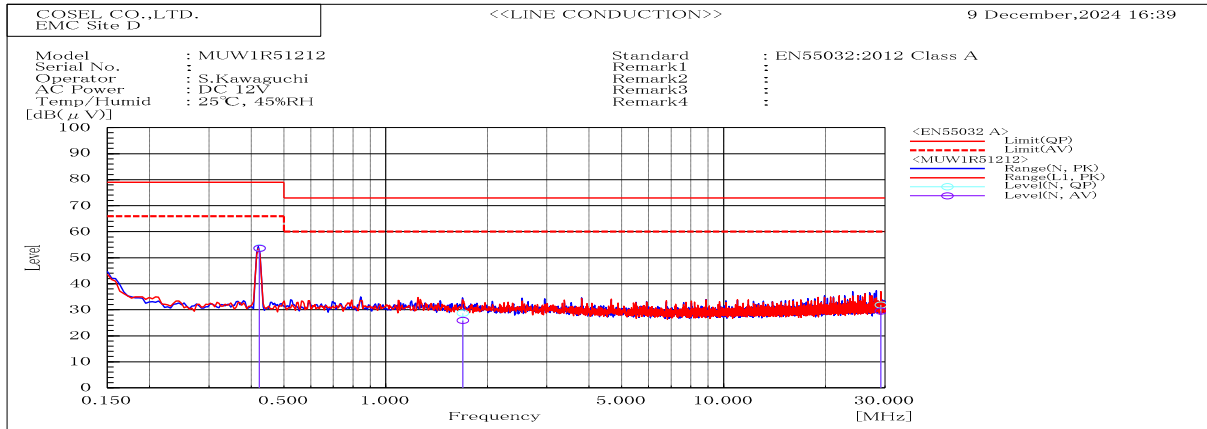
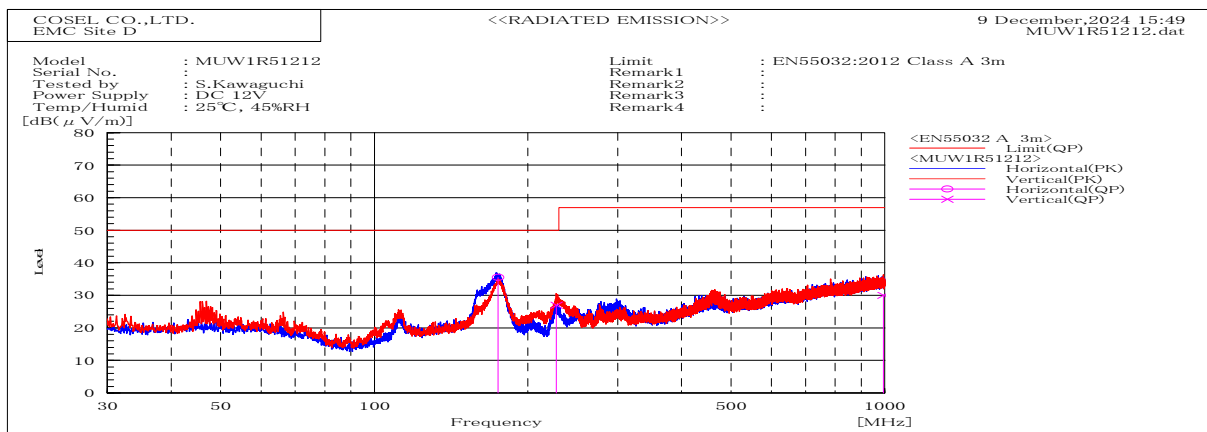


DATA SHEET

Date		05-Mar-25	
Model	MUW1R51212	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	45 %RH
		Tested by	S.Kawaguchi



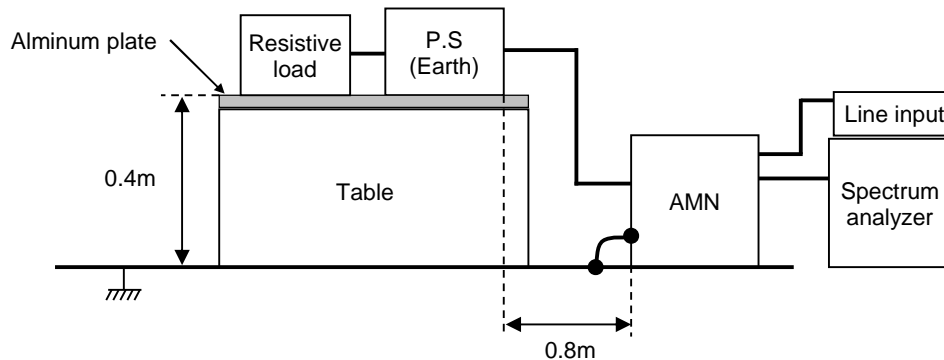
Frequency MHz	Line	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
0.423	N	53.8	53.6	79	66	25.2	12.4	Pass	
1.692	N	28.7	25.9	73	60	44.3	34.1	Pass	
29.193	N	31.9	29.5	73	60	41.1	30.5	Pass	



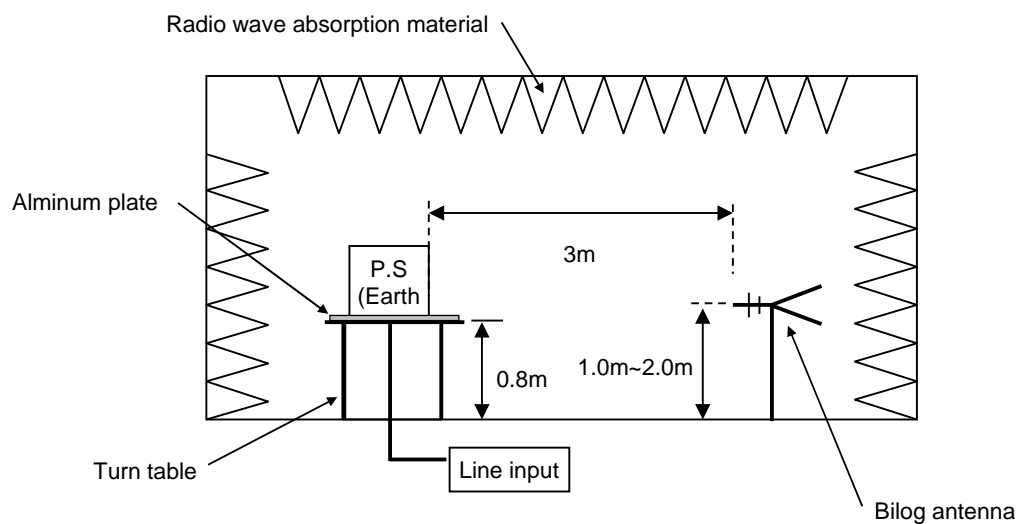
Frequency MHz	Polarization	Stability	Level dB(μV/m)		Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP	QP				
174.68	H	Stable	35.6	50	14.4	Pass	196.3	224.1	
227.503	V	Stable	27	50	23	Pass	100.2	208.2	
994.079	V	Stable	30	57	27	Pass	120.5	49.3	

DATA SHEET		Date	05-Mar-25
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	45 %RH
		Tested by	S.Kawaguchi

1. Line conduction



2. Radiated emission



Conditions

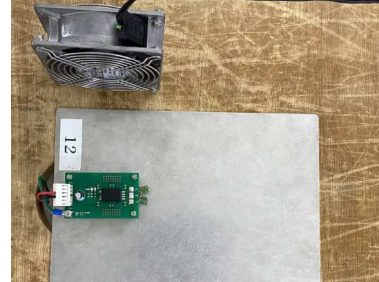
Test : EMI
Model Name: MUW1R5□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

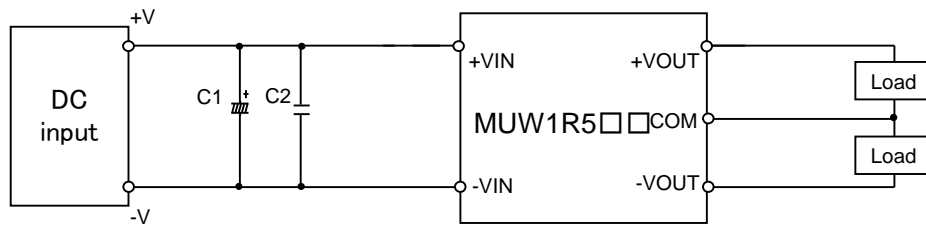


Fig.1 MUW1R505□, MUW1R512□, MUW1R524□ Testing circuitry

- | | | | |
|------|-----------|-----------------|---|
| C1 : | MUW1R505□ | 16V 220 μ F | Electric capacitor (UPWseries NICHICON) |
| | MUW1R512□ | 50V 100 μ F | Electric capacitor (UPWseries NICHICON) |
| | MUW1R524□ | - | |
| C2 : | MUW1R505□ | 16V 22 μ F | Ceramic capacitor (GRM31CC71C226M MURATA MANUFACTURING) |
| | MUW1R512□ | 25V 22 μ F | Ceramic capacitor (C3216JB1E226MT TDK) |
| | MUW1R524□ | 50V 10 μ F | Ceramic capacitor (C3216X7R1H106KT TDK) |

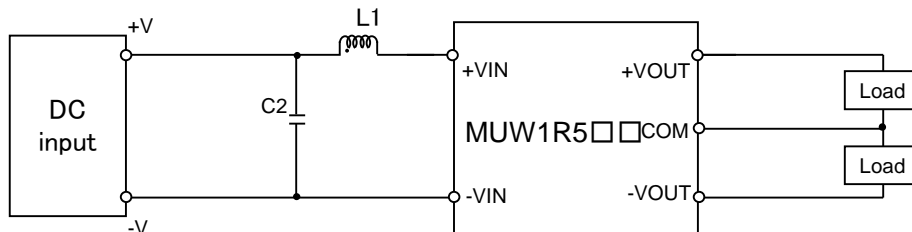


Fig.2 MUW1R548□ Testing circuitry

- | | | | |
|------|-----------|------------------|---|
| C2 : | MUW1R548□ | 100V 2.2 μ F | Ceramic capacitor (C3216X7S2A225KT TDK) |
| L1 : | MUW1R548□ | 520mA 15 μ H | Inductor(LQH32PN150MN0L MURATA MANUFACTURING) |